

**Search Notes**

Application/Control No.

09/653,517

Examiner

Shin-Hon Chen

Applicant(s)/Patent under  
Reexamination

MACKAY ET AL.

Art Unit

2131

**SEARCHED**

Class	Subclass	Date	Examiner

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
USPAT, PGPUB, JPO, EPO, DERWENT (BRS search)	5/24/2006	S.C.